This test system fulfills requirements on HTRB systems for high voltage IGBT devices with high reverse power losses. This system is the only HTRB equipment with continuous measurement of junction temperature under bias voltage up to 2000V.

**Test capacity:** 4 x 80 DUTs

**Test chambers:** 4

**Temperature range:** 50°C to 200°C per chamber

**Test boards per chamber:** 4

**Possible voltage range:**
- 0V to 1600V
- 0V to 2000V

**Power supplies:** Separate power supply for each test board

**Calibration:** Auto-calibration of each DUT before test

**Test mode:**
- Regulation of test temperature after $T_{junction}$
- Regulation of test temperature after $T_{case}$

**Sockets:** Reliable device sockets designed for 200°C

**Operating system:** MS Windows XP

**Handling:** Comfortable graphic platform

**Alarms:** Programmable, light or sound

**System controls:** Continuous for voltages and temperatures of chambers and test boards

**DUT controls:** Continuous for bias voltages, leakage currents and junction temperatures with alarm and disconnection of test board by values over programmable limits